

TEXAS

Pressure

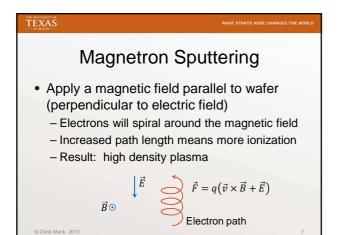
- Argon gas pressure at ~ 0.1 torr
- Resulting mean-free path $\lambda \approx 0.5$ mm
- Many collisions take place as sputtered target material travels to the wafer
- Material arrives at wafer from all angles
 Good step coverage
 - Still some shadowing

Sputter Yield

Sputter yield is defined as

 $Sputter Yield = \frac{\# of \ target \ atoms \ released}{\# of \ ions \ hitting \ target}$

- If ion energy < 10 100 eV, there is no sputtering (yield = 0)
- If ion energy > 10 keV, we get implantation
- We try to get sputter yields between 1 and 2



EXAS

Lecture 22: What have we learned?

- Describe the basic components of a sputter system
- How is good step coverage achieved in a sputtering system?
- Define "sputter yield"
- Explain the operation and effects of magnetron sputtering

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